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Low-temperature NO-adsorption properties of manganese oxide octahedral molecular sieves with different potassium content

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Abbreviations: AOS, average oxidation number; DRIFTS, diffuse reflectance infrared Fourier-transform spectroscopy; FTIR, Fourier-transform infrared; RT, room temperature; SSA, specific surface area; TEM, transmission electron microscopy; TG/DTA, thermogravimetry/differential thermal analysis; XAFS, X-ray absorption fine structure; XPS, X-Ray photoelectron spectroscopy; XRD, X-ray diffraction

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